

Monday 20 March

Metrology aspects
Session | Location: CERN, 503/1-001 - Council Chamber

16:05-16:30 The Shape Evaluating Sensor: High Accuracy and Touchless
Speaker
Ms Claude Sanz

16:30-16:55 Traceable measurements on microparts
Speaker
Dr Alain Küng

16:55-17:20 The application of metrology research in industry
Speaker
Mr Craig Davey